

# XP152 MOSFET



## 20V P-Channel Enhancement-Mode

V<sub>DS</sub> = -20V

R<sub>DS(ON)</sub>, V<sub>GS</sub>@-1.8V, I<sub>DS</sub>@-2.0A = 100mΩ@TYP

R<sub>DS(ON)</sub>, V<sub>GS</sub>@-4.5V, I<sub>DS</sub>@-2.8A = 71mΩ@TYP

R<sub>DS(ON)</sub>, V<sub>GS</sub>@-2.5V, I<sub>DS</sub>@-2.0A = 83mΩ@TYP

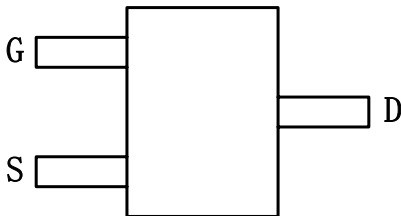
### Features

Advanced trench process technology

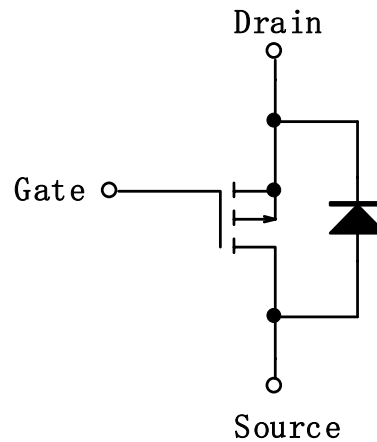
High Density Cell Design For Ultra Low On-Resistance

SOT-23 / SOT-323 / SOT-353

### Internal Schematic Diagram



Top View



P-Channel MOSFET

### Maximum Ratings and Thermal Characteristics (T<sub>A</sub> = 25°C unless otherwise noted)

Parameter	Symbol	Limit	Unit	
Drain-Source Voltage	V <sub>DS</sub>	-20	V	
Gate-Source Voltage	V <sub>GS</sub>	±12		
Continuous Drain Current <sup>1)</sup>	I <sub>D</sub>	-2.2	A	
Pulsed Drain Current <sup>2)</sup>	I <sub>DM</sub>	-8		
Maximum Power Dissipation	P <sub>D</sub>	T <sub>A</sub> =25°C	1.25	W
		T <sub>A</sub> =75°C	0.8	
Operating Junction and Storage Temperature Range		T <sub>J</sub> , T <sub>stg</sub>	-55 to 150	°C
Junction-to-Ambient Thermal Resistance (PCB mounted) <sup>3)</sup>		R <sub>θJA</sub>	140	W/°C

- Note:
1. Fused current that based on wire numbers and diameter
  2. Repetitive Rating: Pulse width limited by the maximum junction temperature
  3. 1-in<sup>2</sup> 2oz Cu PCB board

## ELECTRICAL CHARACTERISTICS

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Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
<b>Static</b>						
Drain-Source Breakdown Voltage	$BV_{DSS}$	$V_{GS} = 0V, I_D = 250\mu A$	20	--	--	V
Drain-Source On-Stage Resistance	$R_{DS(on)}$	$V_{GS} = -4.5V, I_D = -2.8A$	--	71.0	100.0	m $\Omega$
Drain-Source On-Stage Resistance	$R_{DS(on)}$	$V_{GS} = -2.5V, I_D = -2.0A$	--	83.0	150.0	
Drain-Source On-Stage Resistance	$R_{DS(on)}$	$V_{GS} = -1.8V, I_D = -2.0A$	--	100.0	170.0	
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = 250\mu A$	-0.45	-0.61	-0.9	V
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS} = -9.6V, V_{GS} = 0V$	--	--	1	$\mu A$
Gate Body Leakage	$I_{GSS}$	$V_{GS} = \pm 8V, I_{DS} = 0\mu A$	--	--	$\pm 100$	nA
<b>Dynamic<sup>3)</sup></b>						
Total Gate Charge	$Q_g$	$V_{DS} = -6V, I_D = -2.8A$ $V_{GS} = -4.5V$	--	--	--	nC
Gate-Source Charge	$Q_{gs}$		--	--	--	
Gate-Drain Charge	$Q_{gd}$		--	--	--	
Turn-On Delay Time	$t_{d(on)}$	$V_{DD} = -6V, R_L = 6\Omega$ $I_D = -1A, V_{GEN} = -4.5V$ $R_G = 6\Omega$	--	--	--	ns
Turn-On Rise Time	$t_r$		--	--	--	
Turn-Off Delay Time	$t_{d(off)}$		--	--	--	
Turn-Off Fall Time	$t_f$		--	--	--	
Input Capacitance	$C_{iss}$	$V_{DS} = -6V, V_{GS} = 0V$ $f = 1.0MHz$	--	--	--	pF
Output Capacitance	$C_{oss}$		--	--	--	
Reverse Transfer Capacitance	$C_{rss}$		--	--	--	
<b>Source-Drain Diode</b>						
Max. Diode Forward Current	$I_S$	--	--	--	1.6	A
Diode Forward Voltage	$V_{SD}$	$I_S = -1.6A, V_{GS} = 0V$	--	-0.75	--	V

Note: Pulse test: pulse width  $\leq 300\mu s$ , duty cycle  $\leq 2\%$

3. Guaranteed by design; not subject to production testing

